Reflection Geometry "Near-Surface" Small Angle Neutron Scattering (NS-SANS) (but GISANS if you must) and Specular Neutron Reflectometry

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Specular Neutron Reflectometry and what it tells us

Neutron reflection at small angles probes larger scale \underline{depth} structure at an interface on depth scales $\sim 3\mathring{A} - 3000\mathring{A}$

Layered structures or correlations relative to a flat interface: Polymeric, semiconductor and metallic films and multilayers, adsorbed surface structures and complex fluid correlations at solid or free surfaces



Specular reflection

angle of incidence = angle of reflection: $\alpha_f = \alpha_i = \alpha_R$

Reflection scattering <u>vector</u>: $\mathbf{k}_{fR} = \mathbf{k}_i + \mathbf{Q}_{\perp R}$ Perpendicular to surface

Specular Neutron Reflection

Specular Reflection Scattering vector $Q_{\perp R} = 4\pi \sin \alpha_R / \lambda$

Measure: <u>Reflection Coefficient</u> = Specularly reflected intensity / Incident intensity

$$R[Q_{\perp R}] \approx \frac{(4\pi)^2}{Q_{\perp R}^4} \left| \int_z \frac{d\Delta\beta[z]}{dz} \exp[iQ_{\perp R}z] dz \right|^2$$

|1-D FT of depth derivative of scattering contrast|² / $Q_{\perp R}^{4}$

Approximation valid at large $Q_{\perp R}$ of an Optical transform - refraction happens At lower $Q_{\perp R}$ reaches its maximum R=1 i.e. total reflection

but mainly $R \sim 1/Q_{\perp R}^4$ so mostly R <<1

"Near-Surface" (Reflection Geometry) SANS



Neutron Reflectometry (NR)

1 mm deep solution trough beneath polished Quartz slab

In an NR measurement mostly R<<1, so ... what happens to the beam transmitted into a sample ?



mostly Small Angle Neutron Scattering (SANS) happens

Reflection geometry Quartz-Solution cell





1 mm deep solution trough beneath polished Quartz slab

Original idea to simply (and only) use Specular NR to study surface adsorption and constraint effects on complex fluids, in particular under Poiseuille shear so sample flows past quartz surface

MIRROR Reflecometer HFIR c.1994

Trying to measure Poiseuille Shear effects on a threadlike micellar system with Neutron Reflectometry - we had seen a small bump on SPEAR at LANL





"NS-SANS" is SANS in reflection geometry



Machinery of "NS-SANS" corrections (1)

Refraction

Need to correct interface normal component of wavevector in-solution Q_z ' from Q_z



 $\theta'_{i} \cong \sqrt{\alpha_{i}^{2} - \alpha_{c}^{2}} \qquad \theta'_{f} \cong \sqrt{\alpha_{f}^{2} - \alpha_{c}^{2}} \qquad where \quad \alpha_{c} \cong \lambda^{2} (\beta_{s} - \beta_{Q}) / \pi$

 $\beta_{\text{S}},\,\beta_{\text{Q}}$: bulk scattering length densities

Simple Fresnel $Q'_{z} = k(\sin \alpha'_{f} + \sin \alpha'_{t})$ $= k(\sqrt{\sin^{2} \alpha_{f} - \sin^{2} \alpha_{c}} + \sqrt{\sin^{2} \alpha_{t} - \sin^{2} \alpha_{c}})$

Do <u>not</u> need to correct in-plane Wave function continuity condition $=> Q_x'=Qx$ and Qy'=Qy

Machinery of "NS-SANS" corrections (2)

Cross-sections: NR⇔NS-SANS

Total Specular cross-section:



(specular reflection coefficient) (*cell beam acceptance*) (quartz slab absorption) (detector beam fraction 0.71 ± 0.04)

NS-SANS macroscopic cross-section per pixel:

 $\Delta \sigma_{s}(\lambda, \theta_{i}, \theta_{f}) \approx \frac{d\Sigma_{s}}{d\Omega'} [Q_{s}' = (2\pi/\lambda) (Sin\theta_{i}' + Sin\theta_{f}')] \quad (\text{differential cross section})$ $\times \Delta \Omega_{\text{pixel}} \left(\theta_f / \theta_f' \right) \qquad (refraction \ corrected \ pixel \ solid \ angle)$ $\times \frac{1}{2}W L_{s}^{2}/[\cot\theta_{i} + \cot\theta_{f}]$ (geometrical sample volume – wedge) $\times e^{-\mu_{Q}L_{Q}} \times 2 \left[\frac{e^{-(\mu_{s} - \mu_{Q})L_{s}} + ([\mu_{s} - \mu_{Q}]L_{s} - 1)}{([\mu_{s} - \mu_{Q}]L_{s})^{2}} \right]$ (absorption)

(transmission)

Need measurements of superstrate and sample absorption also ITERATIVE

 $\times \left[(1 - R(\theta_i))(1 - R(\theta_f)) \right]$

"Local membrane ordering of sponge phases at a solid-solution interface", W.A. Hamilton, L. Porcar, P.D. Butler and G.G. Warr, Journal of Chemical Physics 116, 8533 (2002)* [and Virtual Journal of Biological Physics Research 3 (2002) [http://www.vjbio.org].

Poiseuille shear response of mixed counterion 20mM 70% CTA35CIBz & 30% CTABr threadlike micelles



In Poiseuille snear past a surface the micelles don't just line up, they form a strongly oriented crystalline hexagonal array...



Our 0.016Å⁻¹ bump was the 01 hexagonal peak above seen from Grazing incidence "Near Surface" SANS data (<~100micron) from surface

W.A. Hamilton, P.D. Butler, S.M. Baker, G.S. Smith, J.B. Hayter, L.J. Magid and R. Pynn, *Physical Review Letters* **72**, 2219 (1994) W.A. Hamilton, P. D. Butler, John B. Hayter, L. J. Magid and P. J. Kreke, *Physica B* **221**, 309 (1996)

NR/NS-SANS



SANS 2D Detector

Penetration of beam into solution ~cm, low angles ~degrees

 \Rightarrow "Near Surface"-SANS probes <~100 μ m from interface

$$d_{eff} \approx \frac{1}{\mu_s \left(\cot \alpha'_i + \cot \alpha'_f\right)}$$

~ Effective penetration depth in terms of sample absorption coefficients and <u>in-solution</u> grazing angles

Micellar separation (interaction) peak: NS-SANS



Volume, Refraction, Interface reflectivity corrections => SANS $d\Sigma/d\Omega$



NS-SANS Corrections + analysis \Rightarrow initial relaxation is 2D melting

"Fast Relaxation of a Hexagonal Poiseuille Shear-induced Near-Surface Phase in a Threadlike Micellar Solution", W.A. Hamilton, P.D. Butler, L.J. Magid, Z. Han and T.M. Slawecki, *Physical Review E (Rapid Communications)* **60**, 1146 (1999)

Imaging Analysis of NR data NB: "Specular" $\alpha_i \equiv \alpha_f$ is a selection rule

□ Mirror is equipped with a 1-D Position Sensitive Detector in reflection plane. Signal is product of source intensity, sample acceptance and reflectivity.

□ High resolution Specular R[Q] can be recovered from data collected across a loosely collimated wide beam. Reduction "automatic" in instrument software.





HFIR reflectomer MIRROR: data after normalization for monitor and sample acceptance (30m SANS satellite 4.75Å - 1993)



W. A. Hamilton, J. B. Hayter, and G. S. Smith, Journal of Neutron Research 2, 1 (1994)

Back to NR - why you might care ... NR-NSSANS on lamellar phase in reflection geometry cell Rough surface (just NS-SANS) vs smooth (strong NR selection)



shows as detector resolution limited specular peak

within incident collimation limited NS-SANS width (surface aligned, but not coherent)

NS-SANS as NR background and monitor: Sponges at a surface

Surfactant "sponge" phase - L_3



Quartz surface

What does an isotropic bulk phase do in an anisotropic situation?

Neutron Reflectometry (NR) and "Near Surface" SANS (NS-SANS) - MIRROR Reflectometer Conventional bulk SANS - "12m" SANS instrument ORNL High Flux Isotope Reactor NR and Off-Specular NS-SANS (in plane) analysis implemented on MIRROR reflectometer

35vol% CetylpyridiniumCl/Hexanol sponge in static Quartz-Solution cell "raw" data



Specular NR signal ($\alpha_i = \alpha_f$) peak at higher Q than and at noticeable offset to ...

Off specular NS-SANS signal (~ parallel to "direct" beam) Sharper than one might have expected for sponge scattering background?

NS-SANS: " L_{α} " near surface? NR: Suppression of membrane fluctuations near interface?

MIRROR Reflectometer - ORNL High Flux Isotope Reactor J. Neutron Research 2, 1 (1994) and http://neutrons.ornl.gov

After partial NS-SANS reduction:

Corrected for refraction, **absorption/volume**, interface transmissions and converted to (Q_x, Q_z) coordinates



1-D PSD Correct for transverse (y) resolution: $Q_s \approx \sqrt{Q_x^2 + (\delta Q_y)^2 + Q_z^2} \dots$

W.A. Hamilton, L. Porcar, P.D. Butler and G.G. Warr,

Journal of Chemical Physics 116, 8533 (2002)* [and Virtual Journal of Biological Physics Research 3 (2002) [http://www.vjbio.org].

[&]quot;Local membrane ordering of sponge phases at a solid-solution interface",

"A comparison shows MIRROR NS-SANS reduction works (can be trusted $\sqrt{)}$..."



"... results are less different than they at first appeared"

Specular Neutron Reflectivity Analysis for sponges at surface



Scattering length density (β[z]) profile normal to interface:

Quartz (β_Q)

Adsorbed bilayer (expected: since CpCl is a cationic surfactant and quartz a negatively charged surface)

Symmetric decaying oscillation to bulk solution membrane concentration (β_s)

Periodicity $\mathbf{d}_{\mathbf{Z}}$ Exponential decay $\boldsymbol{\xi}_{\mathbf{Z}}$ $\mathbf{Z}_{\mathbf{0}}$ offset \Leftrightarrow "1st" in-solution membrane

> ξ_Z / d_Z increases with ϕ_M More surface "layering"

"Local membrane ordering of sponge phases at a solid-solution interface",

W.A. Hamilton, L. Porcar, P.D. Butler and G.G. Warr,

Journal of Chemical Physics 116, 8533 (2002)* [and Virtual Journal of Biological Physics Research 3 (2002) [http://www.vjbio.org].

Simultaneous NR/NS-SANS analysis => layering only at surface and we can be confident about our NR results

Dilution law behavior of length scales



A possible Poiseuille surface shear effect that probably isn't: NS-SANS as a monitor



Fig. 1. (a) Schematic of NR/NS-SANS solution cell and measurement geometry. (b) Raw NR/NS-SANS data set 400 mM CTAB in D_2O at 30 °C. (c) Corrected NS-SANS.

Quartz



Fig. 2. Concentration series: (a) NR scans—rms resolution approximately indicated by data point width; (b) quartzsolution sld profiles; (c) reduced NS-SANS and bulk SANS data; and (d) characteristic lengths vs. concentration.

2(a)&(b) NR: CTAB micelle absorption and some surface ordering

2(c) NS-SANS: (data points) simply agrees with bulk SANS (solid lines)

A possible Poiseuille surface shear effect that probably isn't: NS-SANS as a monitor



Fig. 4. Temperature/"shear" effects on 400 mM CTAB in D2O at a nominal temperature of 35 °C at rest and at an applied Poiseuille surface shear ~3000 Hz: (a) NR measurement in surface layering peak region scaled as RQ_R^4 , and (b) NS-SANS cross-section over the micelle interaction peak region.



Fig. 3. 400 mM CTAB in D_2O temperature series: (a) sld profiles at 30 and 50 °C, and (b) reduced NS-SANS cross-section at 30, 40, and 50 °C over interaction peak region.

4(a) For concentrated 400mM solutions 3000Hz shear apparently sharpens the NR layering peak (consistent with expectations)

but

4(b) corresponding NS-SANS peak shift 0.001Å⁻¹ and -1.5cm⁻¹

&

3(b) previous temperature series show that this could simply correspond to a 2°C temperature rise ... 0.0005Å⁻¹/°C and -0.7cm⁻¹/°C

SO

no premature (or false?) report of a shear-induced effect

"Using Neutron Reflectometry and reflection geometry "Near-Surface" SANS to investigate surfactant micelle organization at a solid-solution interface", W. A. Hamilton, L. Porcar, and L.J. Magid, *Physica B* **357**, 88-93 (2005)

Things to think about

NS-SANS is quite often unavoidable in NR measurements (can be true even in thin liquid films ~20-50micron) You might as well understand it to account for it properly even if only for background subtraction

A rather useful "bulk" sample state monitor So you can be sure of your bulk state and scattering can probe where a sensor might not fit

NR/NS-SANS Analysis: Easy for constant wavelength reactor reflectometers e.g. MIRROR at HFIR-CNS

and

Can be done with SNS Liquids reflectometer (with a few more corrections) NB: and in TOF case fully simultaneous NR and NS-SANS

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"Using Neutron Reflectometry and reflection geometry "Near-Surface" SANS to investigate surfactant micelle organization at a solid-solution interface", W. A. Hamilton, L. Porcar, and L.J. Magid, *Physica B* **357**, 88-93 (2005)